

Title (en)
Improvements in strain gauges.

Title (de)
Dehnungsmessgerät.

Title (fr)
Jauge de contrainte.

Publication
EP 0006740 A1 19800109 (EN)

Application
EP 79301205 A 19790621

Priority
US 92013778 A 19780628

Abstract (en)
A strain gauge element (10) having an elastic beam (11) with field effect transistors (13, 14, 15, 16) deposited on one surface arranged in a Wheatstone bridge so that deformation of the beam (11) produces a proportional imbalance signal across the bridge, and means for applying a gate biasing voltage (^vG) to the transistors with at least one such voltage being adjustable so that the bridge can be electrically balanced for a null or no load condition.

IPC 1-7
G01L 1/18; **G01L 9/06**; **G01R 17/16**; **H01L 29/84**

IPC 8 full level
G01B 7/16 (2006.01); **G01L 1/22** (2006.01); **G01L 9/00** (2006.01); **G01R 17/16** (2006.01); **H01L 29/84** (2006.01)

CPC (source: EP US)
G01L 1/2293 (2013.01 - EP US); **G01R 17/16** (2013.01 - EP US); **H01L 29/84** (2013.01 - EP US)

Citation (search report)

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EP2485028A1; CN102680146A; US8698213B2

Designated contracting state (EPC)
DE FR GB NL

DOCDB simple family (publication)
EP 0006740 A1 19800109; JP S557699 A 19800119; US 4191057 A 19800304

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